Author index

Allmendinger, T., see Mallat, T.	52 (1991) 189	remedy for the indium reduction at	
Alnot, M. and J. Fusy, Hydrogen adsorp-		the In ₂ O ₃ / μ c-Si:C:H interface	52 (1991) 339
tion on cobalt/Pt(110)(1 \times 2) surfaces	52 (1991) 77	Dufour, G., see Zylberajch-Antoine, C.	52 (1991) 323
Andermann, G., see Scimeca, T.	52 (1991) 199	Dyer, M.J., L.E. Jusinski, H. Helm and	
Aucouturier, M., see Casamassima, M.	52 (1991) 205	C.H. Becker, Surface analysis by pho-	
		toionization of sputtered species with	
Bagnoli, P.E., A. Piccirillo, A.L. Gobbi		intense picosecond laser radiation	52 (1991) 151
and R. Giannetti, Electrical charac-			
teristics of silicon nitride on silicon		Eddy, M.M., see Young, K.H.	52 (1991) 85
and InGaAs as a function of the insu-		Elschner, A., see Quadakkers, W.J.	52 (1991) 271
lator stoichiometry	52 (1991) 45	Engelhard, H., A. Goldmann, R. Matz-	(/
Bagnoli, P.E., see Piccirillo, A.	52 (1991) 295	dorf and J. Skonieczny, Angle-re-	
Baiker, A., see Mallat, T.	52 (1991) 189	solved photoemission studies of epi-	
Ball, J., see Treverton, J.A.	52 (1991) 107	taxially grown CuBr films of different	
Barraud, A., see Zylberajch-Antoine, C.	52 (1991) 323	thicknesses on Ag(100)	52 (1991) 235
Beamson, G., see Briggs, D.	52 (1991) 159	Etcheberry, A., see Casamassima, M.	52 (1991) 205
Becker, C.H., see Mouncey, S.P.	52 (1991) 39	,	(,
Becker, C.H., see Dyer, M.J.	52 (1991) 151	Fairlie, M., see Treverton, J.A.	52 (1991) 107
Biliński, B., W. Wójcik and A.L. Dawid-		Feldman, L.C., see Zinke-Allmang, M.	52 (1991) 357
owicz, Gas-adsorption study of the		Fujishima, A., see Zhou, G.	52 (1991) 227
surface dehydroxylation and rehy-		Fusy, J., see Alnot, M.	52 (1991) 77
droxylation of controlled porosity		,	0= (1//1)
glasses	52 (1991) 125	Gaži, M., see Thurzo, I.	52 (1991) 311
Briggs, D. and G. Beamson, Comment on		Giannetti, R., see Bagnoli, P.E.	52 (1991) 45
'Evaluation of polymeric standard		Gobbi, A.L., see Bagnoli, P.E.	52 (1991) 45
reference materials for monitoring the		Gobbi, A.L., see Piccirillo, A.	52 (1991) 295
performance of X-ray photoelectron		Goh, S.H., H.S.O. Chan and K.L. Tan,	0 = (1//1/ =/0
spectrometers' by B.R. Strohmeier	52 (1991) 159	Surface analysis of poly(vinyl chlo-	
		ride)/poly(α -methylstyrene-co-acry-	
Cai, S., see Zhou, G.	52 (1991) 227	lonitrile) blends by X-ray photoelec-	
Carvalho, C., see De Nijs, J.M.M.	52 (1991) 339	tron spectroscopy	52 (1991) 1
Casamassima, M., E. Darque-Ceretti, A.	(,	Goldmann, A., see Engelhard, H.	52 (1991) 235
Etcheberry and M. Aucouturier,		Gröning, P., S. Nowak and L. Schlap-	02 (1),1,200
Acid-base behavior of aluminum and		bach, Temperature-dependent sur-	
silicon oxides - a combination of two		face modifications of AISI 316L and	
approaches: XPS and Lewis acido-		AISI 440C stainless steel substrates	52 (1991) 333
basicity; rest potential and Brönsted		Gustafson, B.L. and P.S. Wehner, XPS	()
acido-basicity	52 (1991) 205	and XRD studies of supported Pd-Cu	
Chan, H.S.O., see Goh, S.H.	52 (1991) 1	bimetallics	52 (1991) 261
		Gutsev, G.L., Yu.M. Shul'ga and V.I.	(,
Darque-Ceretti, E., see Casamassima, M.	52 (1991) 205	Rubtsov, Chemical shifts of the O1s	
Dawidowicz, A.L., see Biliński, B.	52 (1991) 125	core levels for oxygen dimers in	
DeKoven, B.M. and G.E. Mitchell,	(/	$YBa_2Cu_3O_{7-\delta}$: cluster DVM-X α	
HREELS, XPS and in-situ friction		calculations	52 (1991) 329
studies of thin polyphenyl ether films			
on steel surfaces	52 (1991) 215	Harmatha, L., see Thurzo, I.	52 (1991) 311
De Nijs, J.M.M., C. Carvalho, M. Santos		Hegde, R.I., R.E. Jones, Jr., V.S. Kaushik	-4
and R. Martins, A thin SiO layer as a		and P.J. Tobin, Structural integrity	

and thermal stability of TiN/CoSi ₂		Matzdorf, R., see Engelhard, H.	52 (1991) 235
used as local interconnect in a self-		Mitchell, G.E., see DeKoven, B.M.	52 (1991) 215
aligned CoSi ₂ process	52 (1991) 59	Moro, L., see Mouncey, S.P.	52 (1991) 39
Heiland, W., see Van Wyk, G.N.	52 (1991) 351	Mouncey, S.P., L. Moro and C.H. Becker,	
Helm, H., see Dyer, M.J.	52 (1991) 151	High spatial resolution chemical	
Herniman, J., J.S. Yu and A.E. Staton-		imaging of surfaces by combination of	
Bevan, Improved resolution SIMS		a field-emission ion gun and intense	
analysis of annealed Pt/Zn/Pt/		laser radiation	52 (1991) 39
ZrB ₂ /Au ohmic contacts to p-In-			
GaAs on InP substrates using back-		Nágl, V., see Thurzo, I.	52 (1991) 311
surface profiling	52 (1991) 289	Nickel, H., see Quadakkers, W.J.	52 (1991) 271
Hopfmann, Ch., Ch. Werner and J.I.		Nowak, S., see Gröning, P.	52 (1991) 333
Ulacia F., Numerical analysis of fluid			
flow and nonuniformities in a polysili-		Oyama, S.T., see Lewis, K.B.	52 (1991) 241
con LPCVD batch reactor	52 (1991) 169		
		Paál, Z., see Korányi, T.I.	52 (1991) 141
Ibrahim, A., see Zhou, G.	52 (1991) 227	Piccirillo, A., see Bagnoli, P.E.	52 (1991) 45
		Piccirillo, A., R. Marzano, A.L. Gobbi	
James, T.W., see Young, K.H.	52 (1991) 85	and P.E. Bagnoli, Photoluminescence	
Jones, Jr., R.E., see Hegde, R.I.	52 (1991) 59	investigation of III-V semiconductor	
Jusinski, L.E., see Dyer, M.J.	52 (1991) 151	surface damage induced by PECVD	
		silicon nitride films	52 (1991) 295
Kasai, P.H. and P. Wheeler, Degradation		Pinčík, E., see Thurzo, I.	52 (1991) 311
of perfluoropolyethers catalyzed by		Priggemeyer, S., see Van Wyk, G.N.	52 (1991) 351
aluminum chloride	52 (1991) 91		
Kaushik, V.S., see Hegde, R.I.	52 (1991) 59	Quadakkers, W.J., A. Elschner, W. Speier	
Korányi, T.I. and Z. Paál, Correlation of		and H. Nickel, Composition and	
surface composition and thiophene		growth mechanisms of alumina scales	
HDS activity of moderately sulfided		on FeCrAl-based alloys determined	
CoMo/Al ₂ O ₃ catalysts	52 (1991) 141	by SNMS	52 (1991) 271
I DE CALLERY		D	
Lamontagne, B., E. Sacher and M.R.		Rhead, G.E., On the work function	
Wertheimer, Silicon-carbon reaction		changes produced by the coadsorp-	52 (1001) 10
provoked by the sputter cleaning of		tion of alkali metals and hydrogen	52 (1991) 19
lightly contaminated crystalline sili-	E2 (1001) 71	Roberts, M.W., Evidence for the role of	
con	52 (1991) 71 52 (1991) 227	surface transients and precursor states	
Lee, Y.G., see Zhou, G.	52 (1991) 227	in determining molecular pathways in	52 (1001) 122
Lewis, K.B., S.T. Oyama and G.A. So- morjai, TPD studies of vanadium ox-		surface reactions	52 (1991) 133
	52 (1991) 241	Roos, W.D., see Van Wyk, G.N.	52 (1991) 351
ide films deposited on gold Liu, ZM., XL. Zhou and J.M. White,	32 (1991) 241	Roulet, H., see Zylberajch-Antoine, C.	52 (1991) 323
Adsorption and decomposition of		Rubtsov, V.I., see Gutsev, G.L.	52 (1991) 329
trimethylgallium on Pt(111)	52 (1991) 249	Cachan E and Lauranteen D	52 (1001) 71
Loo, B.H., see Zhou, G.	52 (1991) 227	Sacher, E., see Lamontagne, B.	52 (1991) 71
Losch, A., J.W. Schultze and HD.	32 (1991) 221	Santos, M., see De Nijs, J.M.M.	52 (1991) 339
Speckmann, A new electrochemical		Schlapbach, L., see Gröning, P.	52 (1991) 333
method for the determination of the		Schultze, J.W., see Losch, A.	52 (1991) 29
free surface of phosphate layers	52 (1991) 29	Schultze, V. and M. Wagner, Laser-in-	52 (1001) 202
free surface of phosphate layers	32 (1991) 29	duced forward transfer of aluminium Scimeca, T. and G. Andermann, The	52 (1991) 303
Ma Viancui saa Van Dawai	52 (1001) 53		
Ma Xiaocui, see Yan Dawei Mallat, T., T. Allmendinger and A.	52 (1991) 53	characterization of the oxidation of	
Baiker, Oxidation state of lead pro-		Fe by variable exit angle ultrasoft X-	52 (1001) 100
motor on a palladium/carbon catalyst		ray fluorescence spectroscopy Shul'ga, Yu.M., see Gutsev, G.L.	52 (1991) 199 52 (1991) 329
before and during the oxidation of		Sil, A., see Venkateswarlu, D.S.	52 (1991) 329 52 (1991) 7
alcohols	52 (1991) 189	Skonieczny, J., see Engelhard, H.	52 (1991) 235
Martins, R., see De Nijs, J.M.M.	52 (1991) 339	Smith, E.J., see Young, K.H.	52 (1991) 85
Marzano, R., see Piccirillo, A.	52 (1991) 295	Sokolova, M., see Tyuliev, G.	52 (1991) 343
	(02 (1))1) JTJ

Somorjai, G.A., see Lewis, K.B.	52 (1991) 241	Werner, Ch., see Hopfmann, Ch.	52 (1991) 169
Song, L., see Zhou, G.	52 (1991) 227	Wertheimer, M.R., see Lamontagne, B.	52 (1991) 71
Speckmann, HD., see Losch, A.	52 (1991) 29	Wheeler, P., see Kasai, P.H.	52 (1991) 91
Speier, W., see Quadakkers, W.J.	52 (1991) 271	White, J.M., see Liu, ZM.	52 (1991) 249
Staton-Bevan, A.E., see Herniman, J.	52 (1991) 289	Wójcik, W., see Biliński, B.	52 (1991) 125
Strohmeier, B.R., Reply to "Comment of			
D. Briggs and G. Beamson on			
'Evaluation of polymeric standard		Van Dawai and Ma Viaggui Evidence	
reference materials for monitoring the		Yan Dawei and Ma Xiaocui, Evidence	
performance of X-ray photoelectron		for the existence of an interface tran-	
spectrometers' by B.R. Strohmeier"	52 (1991) 163	sition layer for plasma CVD grown	52 (1001) 52
		SnO ₂ /Fe ₂ O ₃ multi-layer films	52 (1991) 53
Tan, K.L., see Goh, S.H.	52 (1991) 1	Yang, H., see Zhou, G.	52 (1991) 227
Thurzo, I., E. Pinčík, L. Harmatha, V.		Young, K.H., E.J. Smith, M.M. Eddy and	
Nágl and M. Gaži, Passivation of shal-		T.W. James, XPS study of thallium	
low donors in GaAs by oxygen plasma		oxidation states in precursor TlBa-	
exposure	52 (1991) 311	CaCuO HTSC thin films	52 (1991) 85
Tobin, P.J., see Hegde, R.I.	52 (1991) 59	Yu, J.S., see Herniman, J.	52 (1991) 289
Treverton, J.A., J. Ball and M. Fairlie,			
The reactions of oxidised aluminium			
surfaces with lubricant additives and		Zhou, G., S. Cai, L. Song, H. Yang, A.	
related compounds	52 (1991) 107	Fujishima, A. Ibrahim, Y.G. Lee and	
Tyuliev, G. and M. Sokolova, Tempera-	32 (1))1) 10/	B.H. Loo, A comparative study of the	
ture dependence of Ni ³⁺ quantity in		inhibition effects of benzotriazole and	
the surface layer of NiO	52 (1991) 343	6-aniline-1,3,5-triazine-2,4-dithiol mo-	
the surface layer of 1410	32 (1771) 343	nosodium salt on the corrosion of	
Ulacia F., J.I., see Hopfmann, Ch.	52 (1991) 169	copper by potentiodynamic polariza-	
Olacia I., 3.1., see Hopfmann, Ch.	32 (1991) 109	tion, AC impedance and surface-en-	
Van Wyk, G.N., S. Priggemeyer, W.D.		hanced Raman spectroscopic tech-	
Roos and W. Heiland, The diffusion		niques	52 (1991) 227
behaviour of Pb in yttrium iron garnet		Zhou, XL., see Liu, ZM.	52 (1991) 249
films	52 (1991) 351	Zinke-Allmang, M. and L.C. Feldman,	32 (1991) 249
Venkateswarlu, D.S. and A. Sil, Imper-	32 (1))1) 331	Scaling and self-similarity in growth	
fect boundaries: thermal response of		of clusters on surfaces	52 (1991) 357
the cathode surface of a potted		Zylberajch-Antoine, C., A. Barraud, H.	32 (1991) 337
heater-cathode assembly	52 (1991) 7	Roulet and G. Dufour, XPS charac-	
nouter cutilode assembly	32 (17)1)	terization of inserted mercury sulfide	
Wagner, M., see Schultze, V.	52 (1991) 303	single layers in a Langmuir-Blodgett	
Wehner, P.S., see Gustafson, B.L.	52 (1991) 261	matrix	52 (1991) 323
	52 (1771) 201	mania	32 (1791) 323

Subject index

Adsorption isotherms		approaches: XPS and Lewis acido- basicity; rest potential and Brönsted	
Gas-adsorption study of the surface de- hydroxylation and rehydroxylation of controlled porosity glasses, B. Biliń-		acido-basicity, M. Casamassima, E. Darque-Ceretti, A. Etcheberry and M. Aucouturier	52 (1991) 205
ski, W. Wójcik and A.L. Dawidowicz	52 (1991) 125		
•		Ammonia	
Alkali metals			
1 West Western		Evidence for the role of surface tran	
On the work function changes produced		Evidence for the role of surface tran- sients and precursor states in deter-	
by the coadsorption of alkali metals		mining molecular pathways in surface	
and hydrogen, G.E. Rhead	52 (1991) 19	reactions, M.W. Roberts	52 (1991) 133
Alloys		Auger electron spectroscopy	
Communities and amounth manhanisms of			
Composition and growth mechanisms of alumina scales on FeCrAl-based al-		Electrical characteristics of silicon nitride	
loys determined by SNMS, W.J.		on silicon and InGaAs as a function	
Quadakkers, A. Elschner, W. Speier		of the insulator stoichiometry, P.E.	
and H. Nickel	52 (1991) 271	Bagnoli, A. Piccirillo, A.L. Gobbi and R. Giannetti	52 (1991) 45
Improved resolution SIMS analysis of an-		Structural integrity and thermal stability	32 (1991) 43
nealed Pt/Zn/Pt/ZrB ₂ /Au ohmic		of TiN/CoSi ₂ used as local intercon-	
contacts to p-InGaAs on InP sub- strates using back-surface profiling, J.		nect in a self-aligned CoSi ₂ process,	
Herniman, J.S. Yu and A.E. Staton-		R.I. Hegde, R.E. Jones, Jr., V.S.	
Bevan	52 (1991) 289	Kaushik and P.J. Tobin	52 (1991) 59
	(,	TPD studies of vanadium oxide films de-	
Aluminium		posited on gold, K.B. Lewis, S.T. Oyama and G.A. Somorjai	52 (1991) 241
Aumunum		A thin SiO layer as a remedy for the	32 (1991) 241
The mantions of suiding delimining		indium reduction at the $In_2O_3/\mu c$	
The reactions of oxidised aluminium sur- faces with lubricant additives and re-		Si:C:H interface, J.M.M. de Nijs, C.	
lated compounds, J.A. Treverton, J.		Carvalho, M. Santos and R. Martins	52 (1991) 339
Ball and M. Fairlie	52 (1991) 107	The diffusion behaviour of Pb in yttrium	
Laser-induced forward transfer of alu-		iron garnet films, G.N. van Wyk, S.	
minium, V. Schultze and M. Wagner	52 (1991) 303	Priggemeyer, W.D. Roos and W. Heiland	52 (1991) 351
Aluminium oxide			
Than than Oxide		Band structure	
Correlation of surface composition and			
thiophene HDS activity of moderately		Chemical shifts of the O 1s core levels for	
sulfided CoMo/Al ₂ O ₃ catalysts, T.I.		oxygen dimers in $YBa_2Cu_3O_{7-\delta}$:	
Korányi and Z. Paál	52 (1991) 141	cluster DVM-X α calculations, G.L.	
Acid-base behavior of aluminum and sil-		Gutsev, Yu.M. Shul'ga and V.I.	
icon oxides - a combination of two		Rubtsov	52 (1991) 329

Subject index 367 Photoluminescence investigation of III-V Carbon semiconductor surface damage induced by PECVD silicon nitride films, Silicon-carbon reaction provoked by the A. Piccirillo, R. Marzano, A.L. Gobbi sputter cleaning of lightly contamiand P.E. Bagnoli 52 (1991) 295 nated crystalline silicon, B. Lamon-A thin SiO layer as a remedy for the tagne, E. Sacher and M.R. Wertindium reduction at the In2O3/µcheimer 52 (1991) 71 Si:C:H interface, J.M.M. de Nijs, C. Oxidation state of lead promotor on a Carvalho, M. Santos and R. Martins 52 (1991) 339 palladium/carbon catalyst before and during the oxidation of alcohols, T. Mallat, T. Allmendinger and A. Chemisorption theory Baiker 52 (1991) 189 Evidence for the role of surface transients and precursor states in deter-Carboxylic acid mining molecular pathways in surface reactions, M.W. Roberts 52 (1991) 133 The reactions of oxidised aluminium surfaces with lubricant additives and re-Cobalt lated compounds, J.A. Treverton, J. 52 (1991) 107 Ball and M. Fairlie Hydrogen adsorption on cobalt/ Pt(110)(1 \times 2) surfaces, M. Alnot and Catalysis J. Fusy 52 (1991) 77 Correlation of surface composition and Correlation of surface composition and thiophene HDS activity of moderately thiophene HDS activity of moderately sulfided CoMo/Al₂O₃ catalysts, T.I. sulfided CoMo/Al₂O₃ catalysts, T.I. Korányi and Z. Paál 52 (1991) 141 Korányi and Z. Paál 52 (1991) 141 Oxidation state of lead promotor on a Compound formation palladium/carbon catalyst before and during the oxidation of alcohols, T. Mallat, T. Allmendinger and A. Silicon-carbon reaction provoked by the 52 (1991) 189 Baiker sputter cleaning of lightly contami-XPS and XRD studies of supported Pdnated crystalline silicon, B. Lamon-Cu bimetallics, B.L. Gustafson and tagne, E. Sacher and M.R. Wert-P.S. Wehner 52 (1991) 261 52 (1991) 71 heimer XPS and XRD studies of supported Pd-Cu bimetallics, B.L. Gustafson and Cathodes P.S. Wehner 52 (1991) 261 Imperfect boundaries: thermal response Copper of the cathode surface of a potted heater-cathode assembly, D.S. Ven-52 (1991) 7 kateswarlu and A. Sil A comparative study of the inhibition effects of benzotriazole and 6-aniline-1,3,5-triazine-2,4-dithiol monosodium Chemical vapour deposition salt on the corrosion of copper by potentiodynamic polarization, AC Evidence for the existence of an interface impedance and surface-enhanced Ra-

52 (1991) 53

52 (1991) 169

man spectroscopic techniques, G.

Zhou, S. Cai, L. Song, H. Yang, A.

Fujishima, A. Ibrahim, Y.G. Lee and

Cu bimetallics, B.L. Gustafson and

XPS and XRD studies of supported Pd-

B.H. Loo

P.S. Wehner

52 (1991) 227

52 (1991) 261

transition layer for plasma CVD

grown SnO₂/Fe₂O₃ multi-layer films,

nonuniformities in a polysilicon

LPCVD batch reactor, Ch. Hopf-

mann, Ch. Werner and J.I. Ulacia F.

Numerical analysis of fluid flow and

Yan Dawei and Ma Xiaocui

Corrosion		Fujishima, A. Ibrahim, Y.G. Lee and B.H. Loo	52 (1991) 227
A new electrochemical method for the determination of the free surface of		Passivation of shallow donors in GaAs by oxygen plasma exposure, I. Thurzo, E. Pinčík, L. Harmatha, V. Nágl and	32 (1771) 221
phosphate layers, A. Losch, J.W. Schultze and HD. Speckmann A comparative study of the inhibition	52 (1991) 29	M. Gaži A thin SiO layer as a remedy for the	52 (1991) 311
effects of benzotriazole and 6-aniline- 1,3,5-triazine-2,4-dithiol monosodium		indium reduction at the $In_2O_3/\mu c$ -Si:C:H interface, J.M.M. de Nijs, C.	
salt on the corrosion of copper by potentiodynamic polarization, AC		Carvalho, M. Santos and R. Martins	52 (1991) 339
impedance and surface-enhanced Raman spectroscopic techniques, G. Zhou, S. Cai, L. Song, H. Yang, A.		Electron energy loss spectroscopy	
Fujishima, A. Ibrahim, Y.G. Lee and			
B.H. Loo	52 (1991) 227	Evidence for the role of surface tran- sients and precursor states in deter- mining molecular pathways in surface	
Cuprous oxide		reactions, M.W. Roberts HREELS, XPS and in-situ friction stud-	52 (1991) 133
Chemical shifts of the O 1s core levels for		ies of thin polyphenyl ether films on	
oxygen dimers in $YBa_2Cu_3O_{7-\delta}$:		steel surfaces, B.M. DeKoven and G.E. Mitchell	52 (1001) 215
cluster DVM-X α calculations, G.L.		Adsorption and decomposition of tri-	52 (1991) 215
Gutsev, Yu.M. Shul'ga and V.I.	52 (1001) 220	methylgallium on Pt(111), ZM. Liu,	
Rubtsov	52 (1991) 329	XL. Zhou and J.M. White	52 (1991) 249
		Temperature dependence of Ni3+ quan-	(,
Diffusion		tity in the surface layer of NiO, G.	
		Tyuliev and M. Sokolova	52 (1991) 343
A thin SiO layer as a remedy for the			
indium reduction at the $In_2O_3/\mu c$ -		Electron microscopy	
Si:C:H interface, J.M.M. de Nijs, C. Carvalho, M. Santos and R. Martins	52 (1991) 339	Electron nucroscopy	
The diffusion behaviour of Pb in yttrium	32 (1991) 339		
iron garnet films, G.N. van Wyk, S.		A new electrochemical method for the	
Priggemeyer, W.D. Roos and W. Hei-		determination of the free surface of	
land	52 (1991) 351	phosphate layers, A. Losch, J.W.	
		Schultze and HD. Speckmann	52 (1991) 29
Electrical properties		Structural integrity and thermal stability	
6.		of TiN/CoSi ₂ used as local interconnect in a self-aligned CoSi ₂ process,	
Electrical characteristics of silicon nitride		R.I. Hegde, R.E. Jones, Jr., V.S.	
on silicon and InGaAs as a function		Kaushik and P.J. Tobin	52 (1991) 59
of the insulator stoichiometry, P.E.		Oxidation state of lead promotor on a	
Bagnoli, A. Piccirillo, A.L. Gobbi and		palladium/carbon catalyst before and	
R. Giannetti	52 (1991) 45	during the oxidation of alcohols, T.	
Evidence for the existence of an interface		Mallat, T. Allmendinger and A.	
transition layer for plasma CVD		Baiker	52 (1991) 189
grown SnO ₂ /Fe ₂ O ₃ multi-layer films, Yan Dawei and Ma Xiaocui	52 (1001) 52	TPD studies of vanadium oxide films de-	
A comparative study of the inhibition	52 (1991) 53	posited on gold, K.B. Lewis, S.T.	52 (1001) 241
effects of benzotriazole and 6-aniline-		Oyama and G.A. Somorjai Composition and growth mechanisms of	52 (1991) 241
1,3,5-triazine-2,4-dithiol monosodium		alumina scales on FeCrAl-based al-	
salt on the corrosion of copper by		loys determined by SNMS, W.J.	
potentiodynamic polarization, AC		Quadakkers, A. Elschner, W. Speier	
impedance and surface-enhanced Ra-		and H. Nickel	52 (1991) 271
man spectroscopic techniques, G.		Laser-induced forward transfer of alu-	,,,
Zhou, S. Cai, L. Song, H. Yang, A.		minium, V. Schultze and M. Wagner	52 (1991) 303

Electron spin resonance		Heterostructures	
Electrical characteristics of silicon nitride on silicon and InGaAs as a function of the insulator stoichiometry, P.E. Bagnoli, A. Piccirillo, A.L. Gobbi and R. Giannetti	52 (1991) 45	Evidence for the existence of an interface transition layer for plasma CVD grown SnO ₂ /Fe ₂ O ₃ multi-layer films, Yan Dawei and Ma Xiaocui Structural integrity and thermal stability of TiN/CoSi ₂ used as local interconnect in a self-aligned CoSi ₂ process.	52 (1991) 53
Epitaxy		nect in a self-aligned CoSi ₂ process, R.I. Hegde, R.E. Jones, Jr., V.S. Kaushik and P.J. Tobin	52 (1991) 59
Angle-resolved photoemission studies of epitaxially grown CuBr films of differ- ent thicknesses on Ag(100), H. Engel- hard, A. Goldmann, R. Matzdorf and J. Skonieczny	52 (1991) 235	Hydrides On the work function changes produced	
Gallium		by the coadsorption of alkali metals and hydrogen, G.E. Rhead	52 (1991) 19
Adsorption and decomposition of trimethylgallium on Pt(111), ZM. Liu,		Hydrogen	
XL. Zhou and J.M. White Gallium arsenide	52 (1991) 249	On the work function changes produced by the coadsorption of alkali metals and hydrogen, G.E. Rhead	52 (1991) 19
		Hydrogen adsorption on cobalt/ Pt(110)(1 × 2) surfaces, M. Alnot and	32 (1991) 19
Passivation of shallow donors in GaAs by oxygen plasma exposure, I. Thurzo, E. Pinčík, L. Harmatha, V. Nágl and M. Gaži	52 (1991) 311	J. Fusy Indium oxide	52 (1991) 77
Glass Gas-adsorption study of the surface de-		A thin SiO layer as a remedy for the indium reduction at the In ₂ O ₃ /μc-Si:C:H interface, J.M.M. de Nijs, C.	
hydroxylation and rehydroxylation of controlled porosity glasses, B. Biliń-	(100)	Carvalho, M. Santos and R. Martins	52 (1991) 339
ski, W. Wójcik and A.L. Dawidowicz	52 (1991) 125	Infrared spectroscopy	
TPD studies of vanadium oxide films deposited on gold, K.B. Lewis, S.T.		Electrical characteristics of silicon nitride on silicon and InGaAs as a function of the insulator stoichiometry, P.E. Bagnoli, A. Piccirillo, A.L. Gobbi and	
Oyama and G.A. Somorjai Halides	52 (1991) 241	R. Giannetti The reactions of oxidised aluminium surfaces with lubricant additives and re-	52 (1991) 45
Degradation of perfluoropolyethers cat-		lated compounds, J.A. Treverton, J. Ball and M. Fairlie	52 (1991) 107
alyzed by aluminum chloride, P.H. Kasai and P. Wheeler	52 (1991) 91	Inorganic compounds	
Angle-resolved photoemission studies of epitaxially grown CuBr films of differ- ent thicknesses on Ag(100), H. Engel- hard, A. Goldmann, R. Matzdorf and J. Skonieczny	52 (1991) 235	The diffusion behaviour of Pb in yttrium iron garnet films, G.N. van Wyk, S. Priggemeyer, W.D. Roos and W. Heiland	52 (1991) 351

Insulator - semiconductor interfaces		Laser processing	
Electrical characteristics of silicon nitride on silicon and InGaAs as a function of the insulator stoichiometry, P.E. Bagnoli, A. Piccirillo, A.L. Gobbi and R. Giannetti Photoluminescence investigation of III–V semiconductor surface damage induced by PECVD silicon nitride films, A. Piccirillo, R. Marzano, A.L. Gobbi and P.E. Bagnoli	52 (1991) 45 52 (1991) 295	High spatial resolution chemical imaging of surfaces by combination of a field-emission ion gun and intense laser radiation, S.P. Mouncey, L. Moro and C.H. Becker Laser-induced forward transfer of aluminium, V. Schultze and M. Wagner Surface analysis by photoionization of sputtered species with intense picosecond laser radiation, M.J. Dyer, L.E. Jusinski, H. Helm and C.H.	52 (1991) 39 52 (1991) 303
Interfaces		Becker	52 (1991) 151
Improved resolution SIMS analysis of annealed Pt/Zn/Pt/ZrB ₂ /Au ohmic contacts to p-InGaAs on InP substrates using back-surface profiling, J. Herniman, J.S. Yu and A.E. Staton-Bevan	52 (1991) 289	Lead Oxidation state of lead promotor on a palladium/carbon catalyst before and during the oxidation of alcohols, T. Mallat, T. Allmendinger and A. Baiker	52 (1991) 189
Ion bombardment		The diffusion behaviour of Pb in yttrium iron garnet films, G.N. van Wyk, S.	32 (1991) 189
Improved resolution SIMS analysis of annealed Pt/Zn/Pt/ZrB ₂ /Au ohmic contacts to p-InGaAs on InP substrates using back-surface profiling, J. Herniman, J.S. Yu and A.E. Staton-Bevan	52 (1991) 289	Priggemeyer, W.D. Roos and W. Heiland Luminescence	52 (1991) 351
Ion scattering Scaling and self-similarity in growth of	32 (1991) 209	Photoluminescence investigation of III-V semiconductor surface damage induced by PECVD silicon nitride films, A. Piccirillo, R. Marzano, A.L. Gobbi and P.E. Bagnoli	52 (1991) 295
clusters on surfaces, M. Zinke-Allmang and L.C. Feldman	52 (1991) 357	Magnesium	
Iron The characterization of the oxidation of Fe by variable exit angle ultrasoft X-		Evidence for the role of surface tran- sients and precursor states in deter- mining molecular pathways in surface reactions, M.W. Roberts	52 (1991) 133
ray fluorescence spectroscopy, T. Scimeca and G. Andermann	52 (1991) 199	Mass spectroscopy	
Iron oxide Evidence for the existence of an interface		High spatial resolution chemical imaging of surfaces by combination of a field-emission ion gun and intense laser	
transition layer for plasma CVD grown SnO ₂ /Fe ₂ O ₃ multi-layer films, Yan Dawei and Ma Xiaocui The characterization of the oxidation of Fe by variable exit angle ultrasoft X-ray fluorescence spectroscopy, T.	52 (1991) 53	radiation, S.P. Mouncey, L. Moro and C.H. Becker Surface analysis by photoionization of sputtered species with intense picosecond laser radiation, M.J. Dyer, L.E. Jusinski, H. Helm and C.H.	52 (1991) 39
Scimeca and G. Andermann	52 (1991) 199	Becker	52 (1991) 151

Composition and growth mechanisms of alumina scales on FeCrAl-based al- loys determined by SNMS, W.J. Quadakkers, A. Elschner, W. Speier and H. Nickel	52 (1991) 271	Fujishima, A. Ibrahim, Y.G. Lee and B.H. Loo XPS characterization of inserted mercury sulfide single layers in a Langmuir—Blodgett matrix, C. Zylberajch-	52 (1991) 227
Molybdenum	32 (1991) 271	Antoine, A. Barraud, H. Roulet and G. Dufour	52 (1991) 323
		0	
Correlation of surface composition and thiophene HDS activity of moderately sulfided CoMo/Al ₂ O ₃ catalysts, T.I. Korányi and Z. Paál	52 (1991) 141	Adsorption and decomposition of trimethylgallium on Pt(111), ZM. Liu,	52 (1001) 240
Nr. 1 1 . 1		XL. Zhou and J.M. White	52 (1991) 249
Nickel oxide		Oxidation	
T		Oxidation	
Temperature dependence of Ni ³⁺ quantity in the surface layer of NiO, G. Tyuliev and M. Sokolova	52 (1991) 343	A new electrochemical method for the determination of the free surface of phosphate layers, A. Losch, J.W.	
Nitric oxide		Schultze and HD. Speckmann XPS study of thallium oxidation states in precursor TlBaCaCuO HTSC thin	52 (1991) 29
Evidence for the role of surface tran- sients and precursor states in deter- mining molecular pathways in surface reactions, M.W. Roberts	52 (1991) 133	films, K.H. Young, E.J. Smith, M.M. Eddy and T.W. James Oxidation state of lead promotor on a palladium/carbon catalyst before and	52 (1991) 85
Nitrides		during the oxidation of alcohols, T. Mallat, T. Allmendinger and A. Baiker	52 (1991) 189
Structural integrity and thermal stability of TiN/CoSi ₂ used as local interconnect in a self-aligned CoSi ₂ process, R.I. Hegde, R.E. Jones, Jr., V.S. Kaushik and P.J. Tobin	52 (1991) 59	Composition and growth mechanisms of alumina scales on FeCrAl-based al- loys determined by SNMS, W.J. Quadakkers, A. Elschner, W. Speier and H. Nickel	52 (1991) 271
Nuclear magnetic resonance		Passivation of shallow donors in GaAs by oxygen plasma exposure, I. Thurzo, E. Pinčík, L. Harmatha, V. Nágl and M. Gaži	52 (1991) 311
Degradation of perfluoropolyethers cat- alyzed by aluminum chloride, P.H.			
Kasai and P. Wheeler	52 (1991) 91	Oxides	
Organic substances		Acid-base behavior of aluminum and silicon oxides – a combination of two	
HREELS, XPS and in-situ friction studies of thin polyphenyl ether films on steel surfaces, B.M. DeKoven and G.E. Mitchell	52 (1991) 215	approaches: XPS and Lewis acido- basicity; rest potential and Brönsted acido-basicity, M. Casamassima, E. Darque-Ceretti, A. Etcheberry and M. Aucouturier	52 (1991) 205
A comparative study of the inhibition effects of benzotriazole and 6-aniline-1,3,5-triazine-2,4-dithiol monosodium		Oxygen	
salt on the corrosion of copper by potentiodynamic polarization, AC impedance and surface-enhanced Raman spectroscopic techniques, G. Zhou, S. Cai, L. Song, H. Yang, A.		Evidence for the role of surface tran- sients and precursor states in deter- mining molecular pathways in surface reactions, M.W. Roberts	52 (1991) 133

52 (1991) 189

52 (1991) 261

Palladium

Oxidation state of lead promotor on a
palladium/carbon catalyst before and
during the oxidation of alcohols, T.
Mallat, T. Allmendinger and A.
Baiker
XPS and XRD studies of supported Pd-
Cu bimetallics, B.L. Gustafson and
P.S. Wehner

Photoelectron spectroscopy

Surface	analysis	s of	poly(viny	chlo	ride)/
poly	(α-meth	ylsty	rene-co-a	crylon	itrile)
blen	ds by X	-ray	photoele	ctron	spec-
trose	copy, S.I	H. G	oh, H.S.C	. Cha	n and
K.L.	Tan				

Evidence for the existence of an interface transition layer for plasma CVD grown SnO₂/Fe₂O₃ multi-layer films, Yan Dawei and Ma Xiaocui

Silicon-carbon reaction provoked by the sputter cleaning of lightly contaminated crystalline silicon, B. Lamontagne, E. Sacher and M.R. Wertheimer

XPS study of thallium oxidation states in precursor TlBaCaCuO HTSC thin films, K.H. Young, E.J. Smith, M.M. Eddy and T.W. James

Evidence for the role of surface transients and precursor states in determining molecular pathways in surface reactions, M.W. Roberts

Correlation of surface composition and thiophene HDS activity of moderately sulfided CoMo/Al₂O₃ catalysts, T.I. Korányi and Z. Paál

Comment on 'Evaluation of polymeric standard reference materials for monitoring the performance of X-ray photoelectron spectrometers' by B.R. Strohmeier, D. Briggs and G. Beam-

Reply to "Comment of D. Briggs and G. Beamson on 'Evaluation of polymeric standard reference materials for monitoring the performance of X-ray photoelectron spectrometers' by B.R. Strohmeier", B.R. Strohmeier

Acid-base behavior of aluminum and silicon oxides - a combination of two

approaches:	XPS	and	Lev	vis	aci	do-
basicity; rest	pote	ntial	and	Br	öns	ted
acido-basicity	y, M.	Cas	sama	ssin	na,	E.
Darque-Cere	tti, A.	Etch	neber	ry a	and	M.
Aucouturier						

HREELS, XPS and in-situ friction studies of thin polyphenyl ether films on steel surfaces, B.M. DeKoven and G.E. Mitchell

Angle-resolved photoemission studies of epitaxially grown CuBr films of different thicknesses on Ag(100), H. Engelhard, A. Goldmann, R. Matzdorf and J. Skonieczny

XPS and XRD studies of supported Pd-Cu bimetallics, B.L. Gustafson and P.S. Wehner

XPS characterization of inserted mercury sulfide single layers in a Langmuir-Blodgett matrix, C. Zylberajch-Antoine, A. Barraud, H. Roulet and G. Dufour

52 (1991) 1 Chemical shifts of the O1s core levels for oxygen dimers in YBa₂Cu₃O_{7-δ}: cluster DVM-Xα calculations, G.L. Gutsev, Yu.M. Shul'ga and V.I. 52 (1991) 53 Rubtsov

Temperature-dependent surface modifications of AISI 316L and AISI 440C stainless steel substrates, P. Gröning, S. Nowak and L. Schlapbach 52 (1991) 71

Temperature dependence of Ni3+ quantity in the surface layer of NiO, G. Tyuliev and M. Sokolova

The diffusion behaviour of Pb in yttrium 52 (1991) 85 iron garnet films, G.N. van Wyk, S. Priggemeyer, W.D. Roos and W. Heiland

Plasma processing

52 (1991) 141

52 (1991) 159

52 (1991) 163

52 (1991) 133

Photoluminescence investigation of III-V semiconductor surface damage induced by PECVD silicon nitride films, A. Piccirillo, R. Marzano, A.L. Gobbi and P.E. Bagnoli

Passivation of shallow donors in GaAs by oxygen plasma exposure, I. Thurzo, E. Pinčík, L. Harmatha, V. Nágl and M. Gaži

A thin SiO layer as a remedy for the indium reduction at the In2O3/µc-Si:C:H interface, J.M.M. de Nijs, C. Carvalho, M. Santos and R. Martins

52 (1991) 205

52 (1991) 215

52 (1991) 235

52 (1991) 261

52 (1991) 323

52 (1991) 329

52 (1991) 333

52 (1991) 343

52 (1991) 351

52 (1991) 295

52 (1991) 311

52 (1991) 339

Platinum Improved resolution SIMS analysis of annealed Pt/Zn/Pt/ZrB2/Au ohmic contacts to p-InGaAs on InP sub-Hydrogen adsorption on cobalt/ strates using back-surface profiling, J. Pt(110)(1 \times 2) surfaces, M. Alnot and Herniman, J.S. Yu and A.E. Staton-52 (1991) 77 Bevan 52 (1991) 289 Adsorption and decomposition of trimethylgallium on Pt(111), Z.-M. Liu, Silicides X.-L. Zhou and J.M. White 52 (1991) 249 Structural integrity and thermal stability **Polymers** of TiN/CoSi2 used as local interconnect in a self-aligned CoSi2 process, Surface analysis of poly(vinyl chloride)/ R.I. Hegde, R.E. Jones, Jr., V.S. $poly(\alpha$ -methylstyrene-co-acrylonitrile) Kaushik and P.J. Tobin 52 (1991) 59 blends by X-ray photoelectron spectroscopy, S.H. Goh, H.S.O. Chan and Silicon K.L. Tan 52 (1991) 1 Degradation of perfluoropolyethers catalyzed by aluminum chloride, P.H. Silicon-carbon reaction provoked by the Kasai and P. Wheeler 52 (1991) 91 sputter cleaning of lightly contami-Comment on 'Evaluation of polymeric nated crystalline silicon, B. Lamonstandard reference materials for montagne, E. Sacher and M.R. Wertitoring the performance of X-ray pho-52 (1991) 71 heimer toelectron spectrometers' by B.R. Numerical analysis of fluid flow and Strohmeier, D. Briggs and G. Beamnonuniformities in a polysilicon 52 (1991) 159 LPCVD batch reactor, Ch. Hopf-Reply to "Comment of D. Briggs and G. mann, Ch. Werner and J.I. Ulacia F. 52 (1991) 169 Beamson on 'Evaluation of polymeric Scaling and self-similarity in growth of standard reference materials for monclusters on surfaces, M. Zinke-Allitoring the performance of X-ray phomang and L.C. Feldman 52 (1991) 357 toelectron spectrometers' by B.R. Strohmeier", B.R. Strohmeier 52 (1991) 163 Silicon nitride Raman scattering Electrical characteristics of silicon nitride on silicon and InGaAs as a function A comparative study of the inhibition of the insulator stoichiometry, P.E. effects of benzotriazole and 6-aniline-Bagnoli, A. Piccirillo, A.L. Gobbi and 1,3,5-triazine-2,4-dithiol monosodium 52 (1991) 45 R. Giannetti salt on the corrosion of copper by Photoluminescence investigation of III-V potentiodynamic polarization, AC semiconductor surface damage inimpedance and surface-enhanced Raduced by PECVD silicon nitride films, man spectroscopic techniques, G. A. Piccirillo, R. Marzano, A.L. Gobbi Zhou, S. Cai, L. Song, H. Yang, A. and P.E. Bagnoli 52 (1991) 295 Fujishima, A. Ibrahim, Y.G. Lee and B.H. Loo 52 (1991) 227 Silicon oxide TPD studies of vanadium oxide films deposited on gold, K.B. Lewis, S.T. Oyama and G.A. Somorjai 52 (1991) 241 Surface analysis by photoionization of sputtered species with intense picosecond laser radiation, M.J. Dyer, Secondary ion mass spectroscopy L.E. Jusinski, H. Helm and C.H. 52 (1991) 151 Becker The reactions of oxidised aluminium sur-Acid-base behavior of aluminum and silfaces with lubricant additives and reicon oxides - a combination of two lated compounds, J.A. Treverton, J. approaches: XPS and Lewis acido-Ball and M. Fairlie 52 (1991) 107 basicity; rest potential and Brönsted

Subject index

acido-basicity, M. Casamassima, E. Darque-Ceretti, A. Etcheberry and M.		Sulphides	
Aucouturier A thin SiO layer as a remedy for the indium reduction at the In ₂ O ₃ /μc-Si:C:H interface, J.M.M. de Nijs, C.	52 (1991) 205	XPS characterization of inserted mercury sulfide single layers in a Langmuir- Blodgett matrix, C. Zylberajch-	
Carvalho, M. Santos and R. Martins	52 (1991) 339	Antoine, A. Barraud, H. Roulet and G. Dufour	52 (1991) 323
Silver		Superconductivity	
Angle-resolved photoemission studies of epitaxially grown CuBr films of different thicknesses on Ag(100), H. Engelhard, A. Goldmann, R. Matzdorf and J. Skonieczny	52 (1991) 235	XPS study of thallium oxidation states in precursor TlBaCaCuO HTSC thin films, K.H. Young, E.J. Smith, M.M. Eddy and T.W. James Chemical shifts of the O 1s core levels for oxygen dimers in YBa ₂ Cu ₃ O _{7-δ} : cluster DVM-Xα calculations, G.L.	52 (1991) 85
Sputtering		Gutsev, Yu.M. Shul'ga and V.I. Rubtsov	52 (1991) 329
High spatial resolution chemical imaging of surfaces by combination of a field-		Surface and interface states	
emission ion gun and intense laser radiation, S.P. Mouncey, L. Moro and C.H. Becker Silicon-carbon reaction provoked by the sputter cleaning of lightly contaminated crystalline silicon, B. Lamon-	52 (1991) 39	Electrical characteristics of silicon nitride on silicon and InGaAs as a function of the insulator stoichiometry, P.E. Bagnoli, A. Piccirillo, A.L. Gobbi and R. Giannetti	52 (1991) 45
tagne, E. Sacher and M.R. Wert- heimer Surface analysis by photoionization of	52 (1991) 71	Surface composition	
sputtered species with intense pi- cosecond laser radiation, M.J. Dyer, L.E. Jusinski, H. Helm and C.H. Becker	52 (1991) 151	Surface analysis of poly(vinyl chloride)/ poly(α-methylstyrene-co-acrylonitrile) blends by X-ray photoelectron spec- troscopy, S.H. Goh, H.S.O. Chan and K.L. Tan High spatial resolution chemical imaging	52 (1991) 1
Steel		of surfaces by combination of a field- emission ion gun and intense laser radiation, S.P. Mouncey, L. Moro and	
A new electrochemical method for the determination of the free surface of phosphate layers, A. Losch, J.W.		C.H. Becker Correlation of surface composition and thiophene HDS activity of moderately	52 (1991) 39
Schultze and HD. Speckmann Surface analysis by photoionization of sputtered species with intense pi- cosecond laser radiation, M.J. Dyer, L.E. Jusinski, H. Helm and C.H.	52 (1991) 29	sulfided CoMo/Al ₂ O ₃ catalysts, T.I. Korányi and Z. Paál Surface analysis by photoionization of sputtered species with intense pi-	52 (1991) 141
Becker HREELS, XPS and in-situ friction studies of thin polyphenyl ether films on steel surfaces, B.M. DeKoven and	52 (1991) 151	cosecond laser radiation, M.J. Dyer, L.E. Jusinski, H. Helm and C.H. Becker	52 (1991) 151
G.E. Mitchell Temperature-dependent surface modifi-	52 (1991) 215	Surface diffusion	
cations of AISI 316L and AISI 440C stainless steel substrates, P. Gröning, S. Nowak and L. Schlapbach	52 (1991) 333	Scaling and self-similarity in growth of clusters on surfaces, M. Zinke-Allmang and L.C. Feldman	52 (1991) 357
2. A.G. and 2. Sommpour	02 (1771) 000	and L.C. I vidilian	J2 (1771) J3 /

Surface energy		Vanadium oxide	
Gas-adsorption study of the surface de- hydroxylation and rehydroxylation of controlled porosity glasses, B. Biliń- ski, W. Wójcik and A.L. Dawidowicz	52 (1991) 125	TPD studies of vanadium oxide films deposited on gold, K.B. Lewis, S.T. Oyama and G.A. Somorjai	52 (1991) 241
Surface segregation		Wetting	
Temperature-dependent surface modifi- cations of AISI 316L and AISI 440C stainless steel substrates, P. Gröning, S. Nowak and L. Schlapbach	52 (1991) 333	HREELS, XPS and in-situ friction studies of thin polyphenyl ether films on steel surfaces, B.M. DeKoven and G.E. Mitchell	52 (1991) 215
Thermal desorption		Work function	
Hydrogen adsorption on cobalt/ Pt(110)(1 × 2) surfaces, M. Alnot and J. Fusy	52 (1991) 77	On the work function changes produced by the coadsorption of alkali metals and hydrogen, G.E. Rhead	52 (1991) 19
TPD studies of vanadium oxide films deposited on gold, K.B. Lewis, S.T.	52 (1001) 241	X-ray diffraction	
Oyama and G.A. Somorjai Adsorption and decomposition of trimethylgallium on Pt(111), ZM. Liu, XL. Zhou and J.M. White	52 (1991) 241 52 (1991) 249	Structural integrity and thermal stability of TiN/CoSi ₂ used as local interconnect in a self-aligned CoSi ₂ process, R.I. Hegde, R.E. Jones, Jr., V.S.	(400)
Tin Scaling and self-similarity in growth of clusters on surfaces, M. Zinke-Allmang and L.C. Feldman	52 (1991) 357	Kaushik and P.J. Tobin XPS and XRD studies of supported Pd— Cu bimetallics, B.L. Gustafson and P.S. Wehner Composition and growth mechanisms of alumina scales on FeCrAl-based al- loys determined by SNMS, W.J.	52 (1991) 59 52 (1991) 261
Tin oxide		Quadakkers, A. Elschner, W. Speier and H. Nickel	52 (1991) 271
Evidence for the existence of an interface transition layer for plasma CVD grown SnO ₂ /Fe ₂ O ₃ multi-layer films, Yan Dawei and Ma Xiaocui	52 (1991) 53	X-ray emission The characterization of the oxidation of	
Titanium		Fe by variable exit angle ultrasoft X-ray fluorescence spectroscopy, T. Scimeca and G. Andermann	52 (1991) 199
Structural integrity and thermal stability of TiN/CoSi ₂ used as local interconnect in a self-aligned CoSi ₂ process, R.I. Hegde, R.E. Jones, Jr., V.S. Kaushik and P.J. Tobin	52 (1991) 59	Composition and growth mechanisms of alumina scales on FeCrAl-based al- loys determined by SNMS, W.J. Quadakkers, A. Elschner, W. Speier and H. Nickel	52 (1991) 271
Tribology		Zinc	
HREELS, XPS and in-situ friction studies of thin polyphenyl ether films on steel surfaces, B.M. DeKoven and G.E. Mitchell	52 (1991) 215	Evidence for the role of surface transients and precursor states in determining molecular pathways in surface reactions, M.W. Roberts	52 (1991) 133